

# Download Electromigration Modeling At Circuit Layout Level

Integrated circuit (IC) reliability is of increasing concern in present-day IC technology where the interconnect failures significantly increases the failure rate for ICs with decreasing interconnect dimension and increasing number of interconnect levels. This feature is not available right now. Please try again later. Integrated circuit (IC) reliability is of increasing concern in present-day IC technology where the interconnect failures significantly increases the failure rate for ICs with decreasing interconnect dimension and increasing number of interconnect levels. Electromigration (EM) of interconnects has

NANYANG TECHNOLOGICAL  
UNIVERSITY 3D ELECTROMIGRATION MODELING AT THE CIRCUIT LAYOUT LEVEL HE FEIFEI  
School of Electrical & Electronic Engineering - Electromigration Modeling At Circuit Layout Level